

Notice of References Cited	Application/Control No. 10/554,383		Applicant(s)/Patent Under Reexamination VRANKEN ET AL.	
	Examiner DANIEL F. MCMAHON		Art Unit 2117	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0099992	07-2002	Distler et al.	714/738
	B	US-			
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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